


<b>Search Notes</b>  	<b>Application/Control No.</b>  10579682	<b>Applicant(s)/Patent Under Reexamination</b>  BAKALASH ET AL.
	<b>Examiner</b>  HAU H NGUYEN	<b>Art Unit</b>  2628

SEARCHED			
Class	Subclass	Date	Examiner
345	505, 506, 519, 520, 419	1/30/10	HN

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Search US-PGPUB; USPAT; FPRS; EPO; JPO; IBM_TDB text search updated	1/30/10	HN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/HAU H NGUYEN/ Primary Examiner.Art Unit 2628
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